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Status	Product Specification
FAST Products	

FAST 74F257, 74F257A

Data Selectors/Multiplexers

74F257 Quad 2-Line To 1-Line Selector/Multiplexer, Non-Inverting (3-State)

74F257A Quad 2-Line To 1-Line Selector/Multiplexer, Non-Inverting (3-State)

FEATURE

- Multifunction capability
- Non-Inverting data path
- 3-state outputs
- See 'F258A for inverting version

DESCRIPTION

The 74F257/74F257A has four identical 2-input multiplexers with 3-state outputs which select 4 bits of data from two sources under control of a common Select (S) input. The I_{0n} inputs are selected when the common Select input is Low and the I_{1n} inputs are selected when the common Select input is High. Data appears at the outputs in true non-inverted form from the selected inputs. The 'F257/' 'F257A is the logic implementation of a 4-pole, 2-position switch where the position of the switch is determined by the logic levels supplied to the common Select input. Outputs are forced to a high impedance "off" state when the Output Enable (\overline{OE}) is High. All but one device must be in high impedance state to avoid currents that would exceed the maximum ratings if the outputs were tied together. Design of the Output Enable signals must ensure

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F257	4.3ns	12mA
74F257A	4.3ns	12mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$; $T_A = 0^\circ C$ to $+70^\circ C$
16-Pin Plastic DIP	N74F257N, N74F257AN
16-Pin Plastic SO	N74F257D, N74F257AD

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

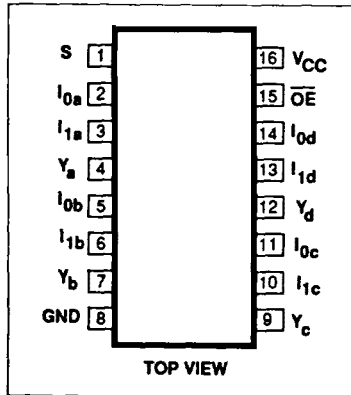
PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
I_{0n}, I_{1n}	Data inputs	1.0/1.0	20 μ A/0.6mA
S	Common Select input	1.0/1.0	20 μ A/0.6mA
\overline{OE}	Output Enable input (active Low)	1.0/1.0	20 μ A/0.6mA
Y_a, Y_b, Y_c, Y_d	Data outputs	150/33	3.0mA/20mA

NOTE 1

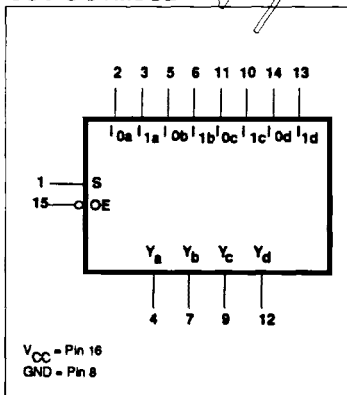
(1) FAST Unit Load is defined as: 20 μ A in the High state and 0.6mA in the Low state.

that there is no overlap when outputs of 3-state devices were tied together. The 74F257A is the faster version of 74F257.

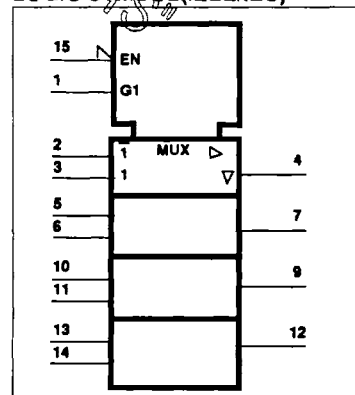
PIN CONFIGURATION



LOGIC SYMBOL



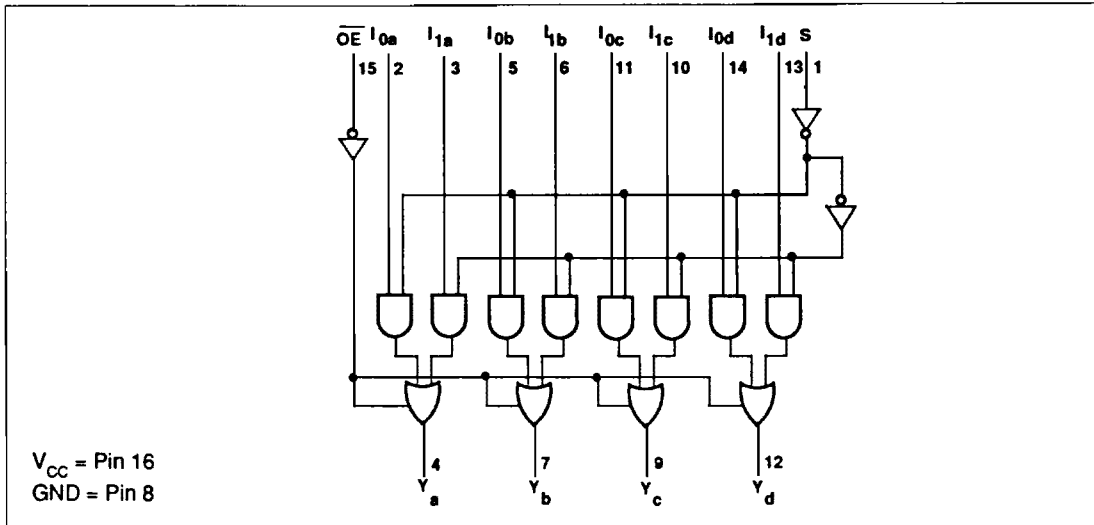
LOGIC SYMBOL (IEEE/IEC)



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LOGIC DIAGRAM



FUNCTION TABLE

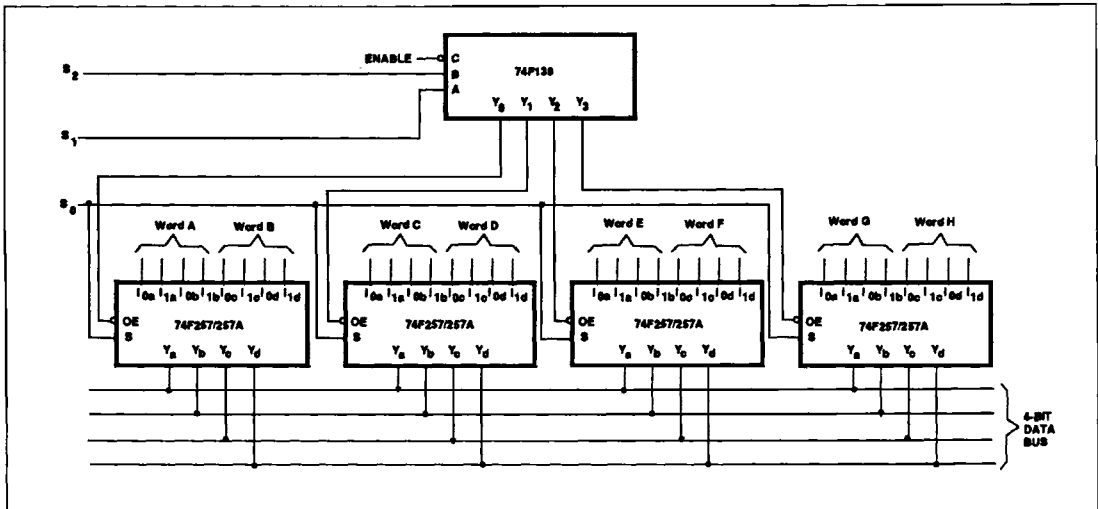
INPUTS				OUTPUT
\overline{OE}	S	I_0	I_1	\overline{Y}
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

- H = High voltage level
- L = Low voltage level
- X = Don't care
- Z = High impedance "off" state

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APPLICATION



ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to +V _{CC}	V
I _{OUT}	Current applied to output in Low output state	48	mA
T _A	Operating free-air temperature range	0 to +70	°C
T _{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _H	High-level input voltage	2.0			V
V _L	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-3	mA
I _{OL}	Low-level output current			24	mA
T _A	Operating free-air temperature range	0		70	°C

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DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS ¹		LIMITS			UNIT
					Min	Typ ²	Max	
V _{OH}	High-level output voltage		V _{CC} = MIN, V _{IL} = MAX V _{IH} = MIN, I _{OH} = MAX	±10%V _{CC}	2.4			V
				±5%V _{CC}	2.7	3.3		V
V _{OL}	Low-level output voltage		V _{CC} = MIN, V _{IL} = MAX V _{IH} = MIN, I _{OL} = MAX	±10%V _{CC}		0.35	0.50	V
				±5%V _{CC}		0.35	0.50	V
V _{IK}	Input clamp voltage		V _{CC} = MIN, I _I = I _{IK}			-0.73	-1.2	V
I _I	Input current at maximum input voltage		V _{CC} = MAX, V _I = 7.0V				100	µA
I _{IH}	High-level input current		V _{CC} = MAX, V _I = 2.7V				20	µA
I _{IL}	Low-level input current		V _{CC} = MAX, V _I = 0.5V				-0.6	mA
I _{OZH}	Off state output current, High-level voltage applied		V _{CC} = MAX, V _O = 2.7V				50	µA
I _{OZL}	Off state output current, Low-level voltage applied		V _{CC} = MAX, V _O = 0.5V				-50	µA
I _{OS}	Short circuit output current ³		V _{CC} = MAX			-60	-150	mA
I _{CC}	Supply current ⁴ (total)	'F257	V _{CC} = MAX	I _{CCH}		9.0	16.0	mA
				I _{CCL}		14.5	22.0	mA
				I _{CCZ}		15.0	23.0	mA
		'F257A		I _{CCH}		9.0	15.0	mA
				I _{CCL}		14.5	22.0	mA
				I _{CCZ}		15.0	23.0	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V_{CC} = 5V, T_A = 25°C.
- Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed lastly.
- Measure I_{CC} with all outputs open and inputs grounded.

AC ELECTRICAL CHARACTERISTICS for 'F257

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			T _A = +25°C			T _A = 0°C to +70°C			
			Min	Typ	Max	Min	Max	Max	
t _{PLH} t _{PHL}	Propagation delay I _n to Y _n	Waveform 1	V _{CC} = 5V C _L = 50pF R _L = 500Ω			V _{CC} = 5V ±10% C _L = 50pF R _L = 500Ω			ns
			3.0	4.5	6.0	3.0	7.0	7.0	
t _{PLH} t _{PHL}	Propagation delay S to Y _n	Waveform 1	V _{CC} = 5V C _L = 50pF R _L = 500Ω			V _{CC} = 5V ±10% C _L = 50pF R _L = 500Ω			ns
			4.5	8.0	13.0	4.5	15.0	9.5	
t _{PZH} t _{PZL}	Output Enable time to High or Low level	Waveform 2	V _{CC} = 5V C _L = 50pF R _L = 500Ω			V _{CC} = 5V ±10% C _L = 50pF R _L = 500Ω			ns
		Waveform 3	3.0	6.0	7.5	3.0	8.5	8.5	
t _{PHZ} t _{PLZ}	Output Disable time from High or Low level	Waveform 2	V _{CC} = 5V C _L = 50pF R _L = 500Ω			V _{CC} = 5V ±10% C _L = 50pF R _L = 500Ω			ns
		Waveform 3	2.0	4.0	6.0	2.0	7.0	7.0	

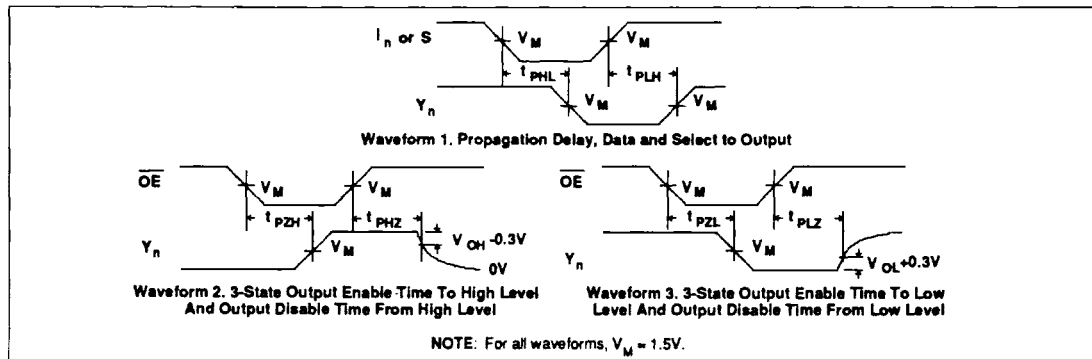
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AC ELECTRICAL CHARACTERISTICS for 'F257A

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation delay I _n to Y _n	Waveform 1	3.0 2.0	4.5 3.5	6.0 5.0	3.0 2.0	7.0 6.0	ns
t_{PLH} t_{PHL}	Propagation delay S to Y _n	Waveform 1	5.5 4.0	7.5 5.5	9.5 7.0	5.0 4.0	10.5 8.0	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level	Waveform 2 Waveform 3	4.5 4.5	6.5 6.0	7.5 7.5	4.5 4.5	8.5 8.5	ns
t_{PHZ} t_{PLZ}	Output Disable time from High or Low level	Waveform 2 Waveform 3	2.0 2.0	4.0 3.5	5.5 5.5	2.0 2.0	6.0 6.0	ns

AC WAVEFORMS



TEST CIRCUIT AND WAVEFORMS

